Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/768,507	MAIER ET AL.
Examiner	Art Unit

John J. Figueroa

1796

,	SEARCHED			
Class	Subclass	Date	Examiner	
525	536	10/31/2007	JJF	
528	171	10/31/2007	JJF	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
525	536	10/31/2007	JJF		
528	171	10/31/2007	JJF		

(INCLUDING SEARCH		<u> </u>
	DATE	EXMR
STIC (review chemical Structure Search)	10/31/2007	JJF
EAST (searched key terms in class 525/535; 525/536; 528/171; 528/174; ; interference search; search strategy attached)	10/31/2007	\ JJF
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